

VAN RHEE ET AL. -- 10/796,309
Client/Matter: 081468-0308602

IN THE SPECIFICATION:

Please amend paragraph [0064] as follows:

In at least one embodiment, the processor 8 is arranged to filter out obvious errors such as measurement errors, local dirt on the substrate, or a focus spot itself. This is achieved by repeating all actions shown in figure 4 but with a so-called feedback height map (not shown) instead of with a measured height map 50. This feedback height map is fabricated by ~~removing height information from the subtracted height map 66 of dies that overlap with the determined focus spots 68. (In another embodiment, the feedback height map may be fabricated by removing, from the measured height map 50, height information of dies that overlap with the determined focus spots.)~~